

Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/763,206	NAKAMURA ET AL.	
Examiner	Art Unit	
Christopher RoDee	1756	

SEARCHED					
Class	Subclass	Date	Examiner		

TMI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEAR (INCLUDING SI	CH NOT EARCH	ES STRATEGY	)
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